

SHEET 1 OF 2

## LIST OF ART CITED BY APPLICANT

(PTO-1449)

ATTY. DOCKET NO.  
P-0601APPLN. SERIAL NO.  
10/733,515

APPLICANT(S)

Choong-Jae LEE

FILING DATE

December 12, 2003

GROUP

2615

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
/PD/	5,002,184	3/1991	LLOYD, Graham P.			
↓	5,689,824	11/1997	NAGAI, Michio			
	6,011,699	1/2000	MURRAY et al.			

## U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	
/PD/	2004/0038703	2/2004	NOTO et al.			
↓	2005/0141187	6/2005	SHIMIZU, Masahito			
	2006/0110608	5/2006	AZUMI et al.			

## U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PUBLICATION NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
/PD/	1998-0057623	10/1998	Korea (Eng. Abstract and Full Korean Text)			X	
↓	2001-0027039	4/2001	Korea (Eng. Abstract and Full Korean Text)			X	
	2002-0066806	8/2002	Korea (Eng. Abstract and Full Korean Text)			X	

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

Not in	<del>Korean Office Action dated October 16, 2004</del>
English.	<del>Korean Office Action dated October 21, 2004</del>
	<del>Korean Office Action dated October 27, 2004</del>

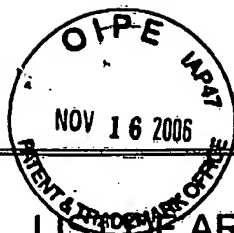
EXAMINER

/Phylesha Dabney/

DATE CONSIDERED

03/13/2007

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.



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EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
/PD/	JP 09-283950	10/1997	JAPAN (English Abstract and Japanese Full Text)			X	
↓	CN 2414554Y	1/2001	CHINA (English Abstract and Chinese Full Text)			X	
↓	CN 2447830Y	9/2001	CHINA (English Abstract and Chinese Full Text)			X	
↓	CN 1375976	10/2002	CHINA (English Abstract and Chinese Full Text)			X	

**OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)**

Chinese Office Action dated December 10, 2004

EXAMINER

/Phylesha Dabney/

DATE CONSIDERED

03/13/2007

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